



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Applicant:

Ofer DU-NOUR

Serial No.: 09/762,473

Filed: February 7, 2001

Group Art Unit: 2877

For: Method and Apparatus for Measuring the
Thickness of a Transparent Film,
Particularly of a Photoresist Film on a
Semiconductor Substrate

Attorney
Docket: 24982
Previously 1639/14

Examiner: Samuel A. Turner

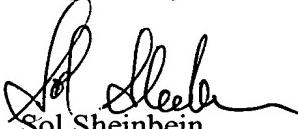
Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

FORMAL DRAWINGS

Sir:

We enclose herewith replacement formal drawings (12-sheets) for the above-identified patent application.

Respectfully submitted,


Sol Sheinbein
Registration No. 25,457

Date: February 18, 2004